

<b>Notice of References Cited</b>	Application/Control No. 10/530,558		Applicant(s)/Patent Under Reexamination TAKEI ET AL.	
	Examiner Lezah W. Roberts		Art Unit 1614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,174,935	01-2001	Matsunae et al.	523/118
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	EP 0 173 567	03-1986	EP	Ying	
	O	EP 0 980 682	02-2000	EP	Nakatsuka	
	P					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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